

N4000-13

**High Speed Low Loss
Multifunctional
Laminate and Prepreg**

Product line & Major Properties

Product	TG	Z-CTE	Dk	Description
N4000-2	135°C	4.5 %	4.4	Multifunctional Epoxy
N4000-2NF	125°C	4.5 %	4.4	Multifunctional Epoxy no Flow
N4000-2EF	130°C	4.2 %	4.4	Halogen-free Multifunct'l Epoxy
N4000-6	175°C	3.9 %	4.4	Multifunctional Epoxy
N4000-6NF	175°C	3.9 %	4.4	Multifunctional Epoxy no Flow
N4000-7	155°C	3.7 %	4.5	Low CTE Multifunctional Epoxy Pass CAF test, Q1000 (-40 ~ +125) and Bosch test
N4000-7MF	155°C	3.7 %	4.5	Low CTE, Modified Flow
N4000-7SI	155°C	3.7 %	3.9	Low CTE, Low Dk Epoxy
N4000-11	175°C	3.2%	4.3	Low CTE, Multifunctional Epoxy Pass CAF test

Product line & Major Properties

Product	TG	Z-CTE	Dk	Description
N4000-13	210°C	3.5 %	3.9	High Speed, Low Loss Epoxy Pass CAF test
N4000-13SI	210°C	3.5 %	3.6	High Speed, Low Loss Epoxy

Lazer drillable glass for N4000-2, -6, -7, -13 resin system

N5000	185°C	3.8 %	4.1	BT Epoxy
N7000-2HT	260°C	2.5 %	4.4	Non-MDA Polyimide
N4500-6T	180°C	4.0 %	3.9	Thermount
N8000	250°C	2.5 %	3.8	Cyanate Ester
N9000	-	71 ~ 260 ppm/°C	2.08 ~ 3.5	RF / Microwave PTFE

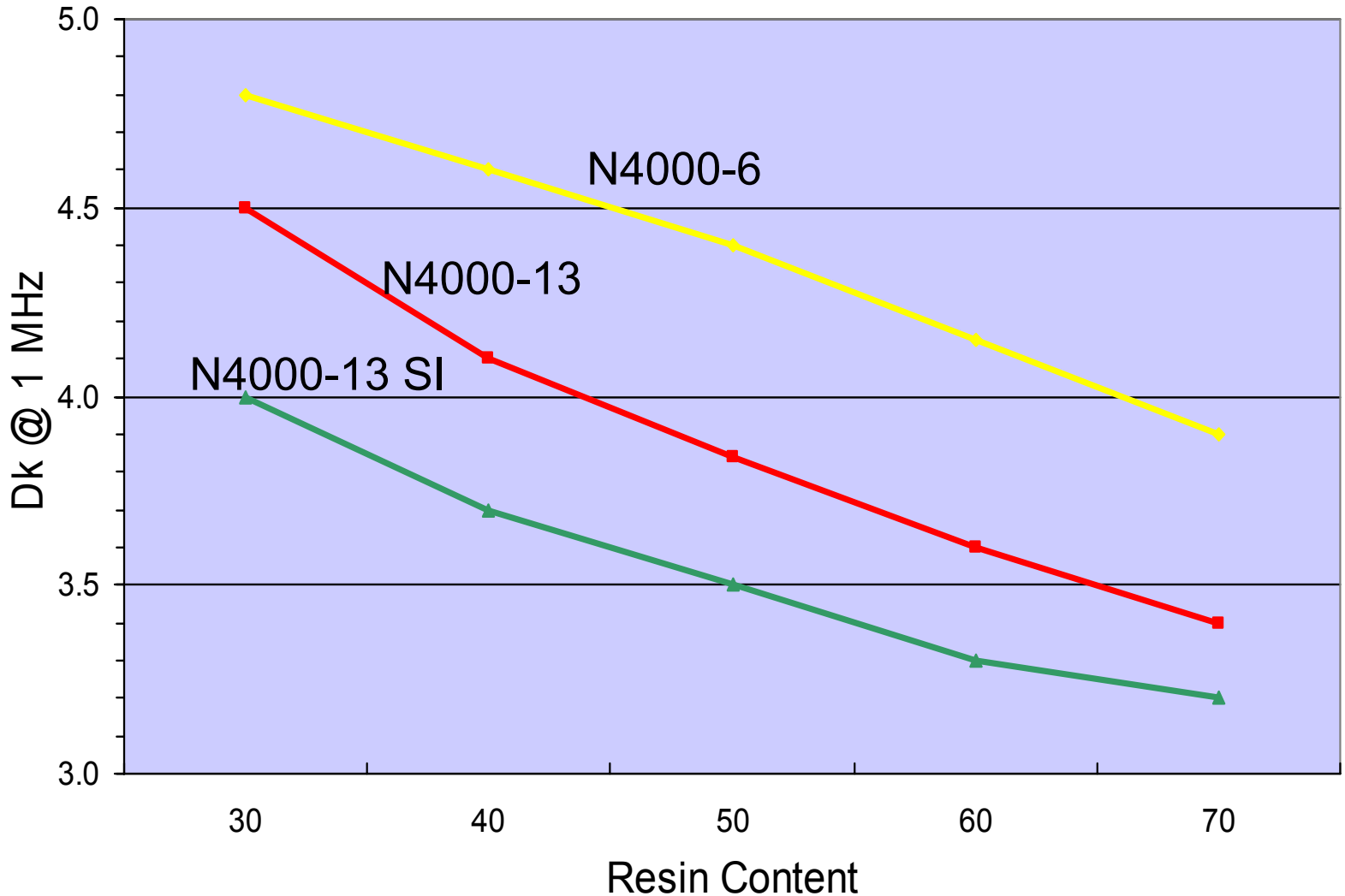
Fonts in **BLACK** are products produced in Singapore

N4000-13 For Faster PCB

	N4000-6	N4000-13
Tg DSC (°C)	175	210
TMA (°C)	170	200
DMA (°C)	185	240
Z-CTE*	3.9%	3.5%
X/Y CTE _(-40°C~+125°C)	12~16 ppm/°C	10~14 ppm/°C
T ₂₆₀ Test	4-8min	+30 min
Degradation Temp	300°C	350°C
Dk @ 1 MHz	4.4	3.9
Dk @ 1 GHz	4.0	3.8
Df @ 1 MHz	0.027	0.009

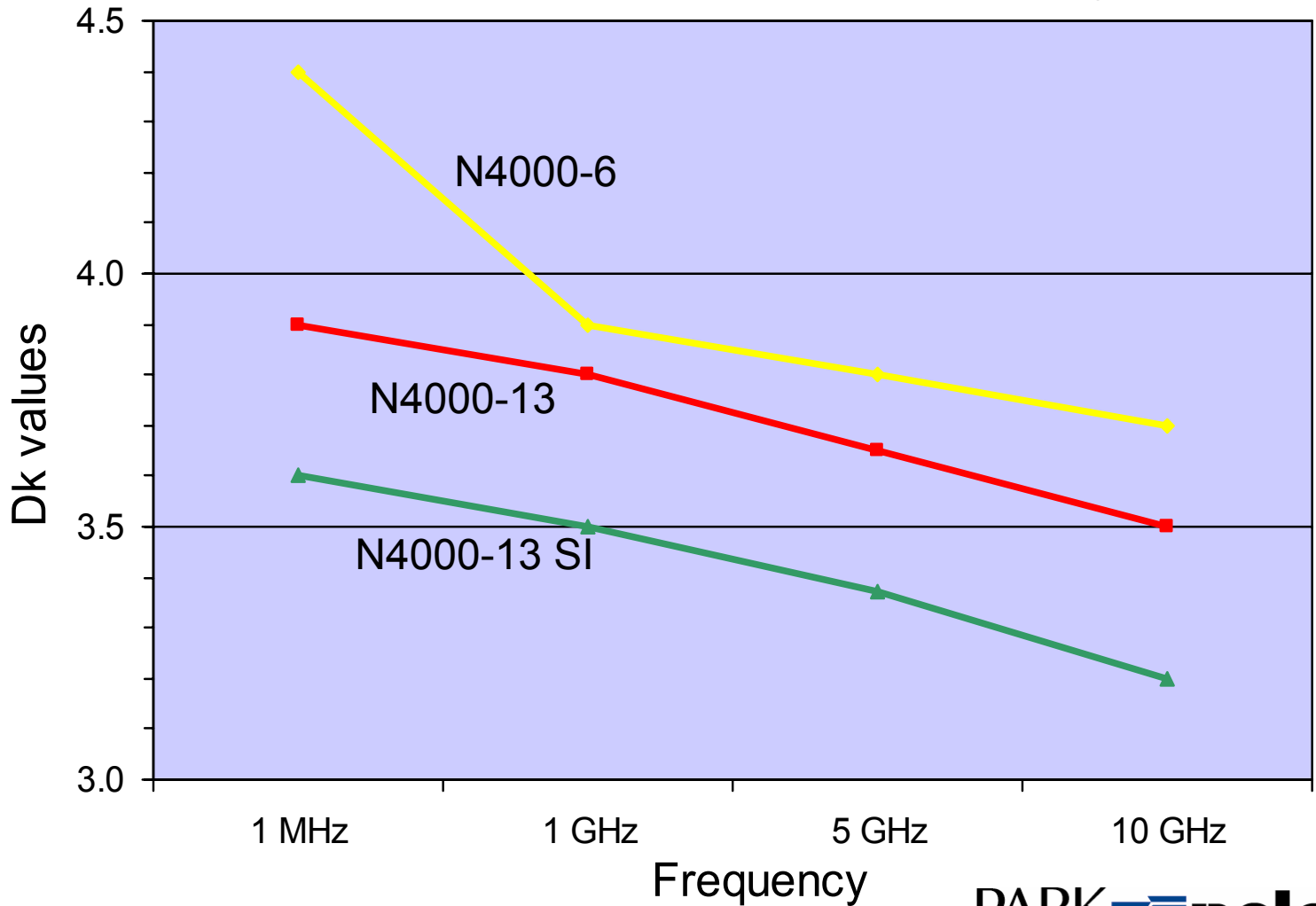
* Between 50 C to 288 C

N4000-13 Electrical Properties



N4000-13 Electrical Properties

- Consistent Dk over frequency



Conductive Anodic Filaments

Testing

Coupons manufactured according to Sun Microsystems design for Park/Nelco by Speedy Circuits.

CAF resistance test performed per Tellabs specification GR-78-CORE PAR. 13.1.5

Stabilize : 96 hrs @ 65°C/ 85%Rh

Testing : 100V DC, 65°C/ 85%Rh @ 10V supply

Pass 500 hours testing.

Processing Guideline

Inner Layer Oxide :

Type Of Chemistry:

Black Oxide with DMAB

Brown Oxide with DMAB

Weight gain:

0.2 - 0.4 mg/cm²

Bake for 30 to 45 min @ 110°C prior to
Lamination

DMAB – Dimethylamine Borane

Processing Guideline

Lamination :

Press : Vacuum Hydraulic

Pressure : 300 - 350 psi

Heat rise : 3 to 6 °C /min (70 - 140 °C)

Curing : 90 min @ 194 °C (product temp.)

Platen temp. : 200 °C

Vacuum : -28" Hg

Typical hot press cycle : 3 hrs

Processing Guideline

Drilling :

Dill Size (mils)	Feed (IPM)	SFPM	Chip load (mils)	Hit count	Retract (IPM)
9.8	40	256	0.4	500	500
13.8	80	361	0.8	1000	1000
19.7	78	400	1.0	1000	1000
27.6	83	400	1.5	1200	1000
31.5	73	400	1.5	1500	1000

Bake the material for 3 hrs @ 180°C after drilling

Processing Guideline

Desmearing :

- **Plasma** is highly recommended
- Chemical desmearing

Apply low Tg condition:

Butyl OH Temp : 65 ~ 78 °C

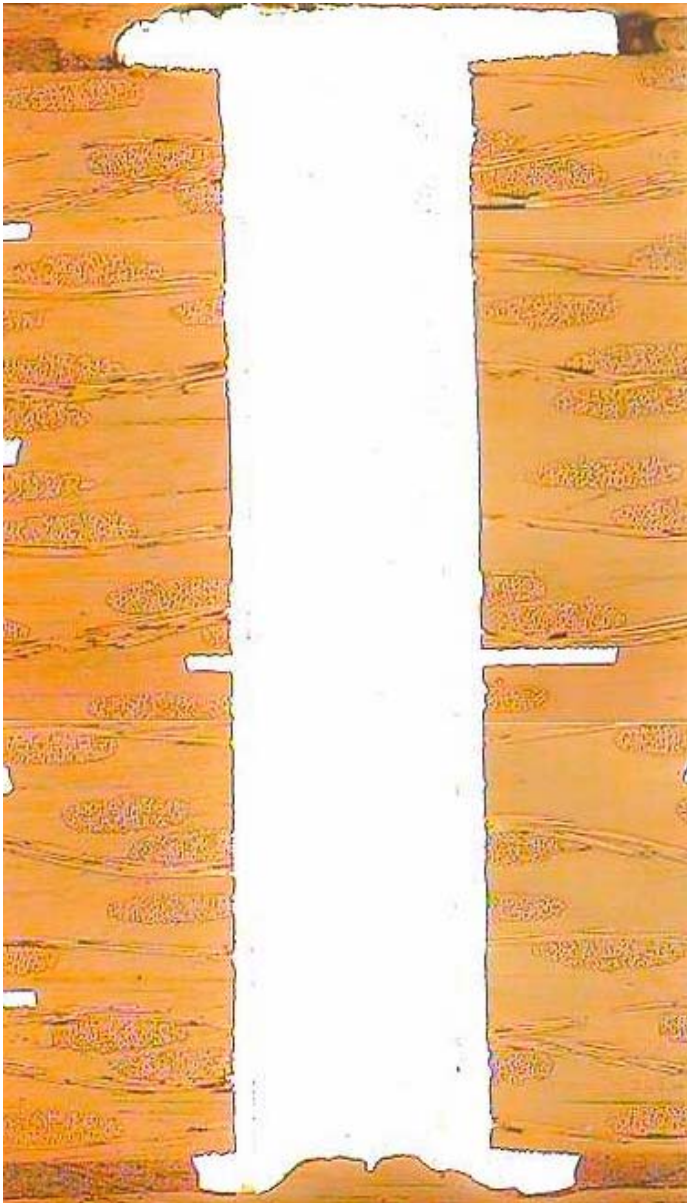
Time : 4 ~ 6 min

KMnO₄ Temp : 79 °C

Time : 8 - 12 min

ONE pass

Application (I)



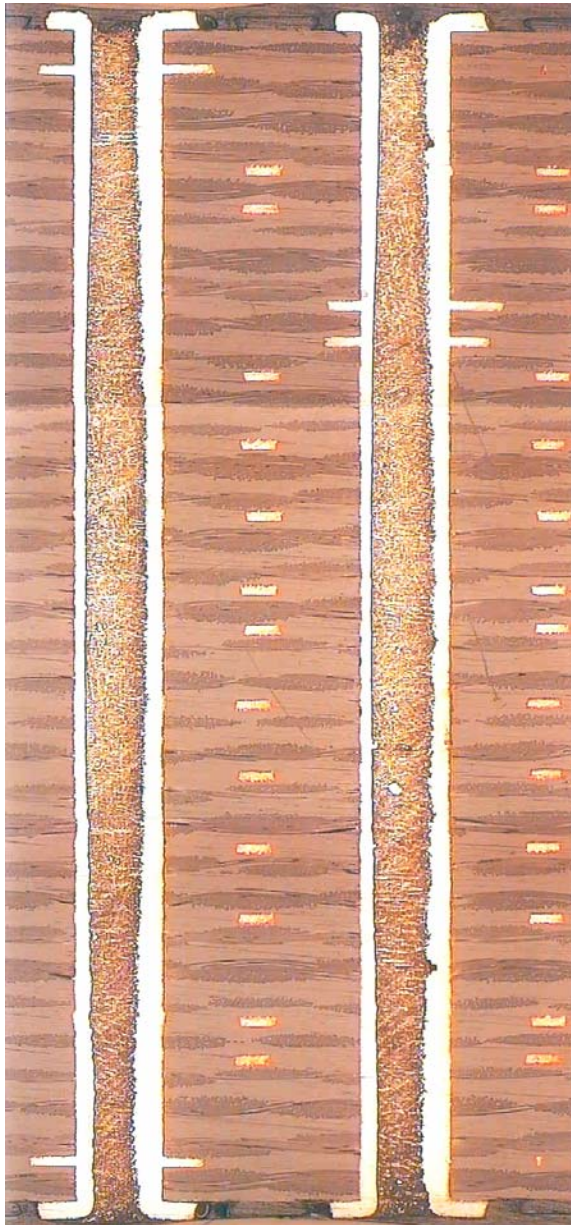
Application : Communication Card

Layer count : 12 layer

Test Results:

- Pass 5 times 288 °C solder float
- No hole wall separation
- No resin recession

Application (III)



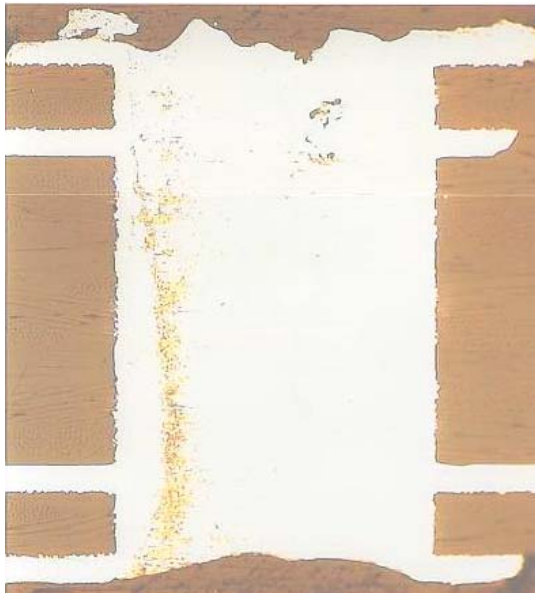
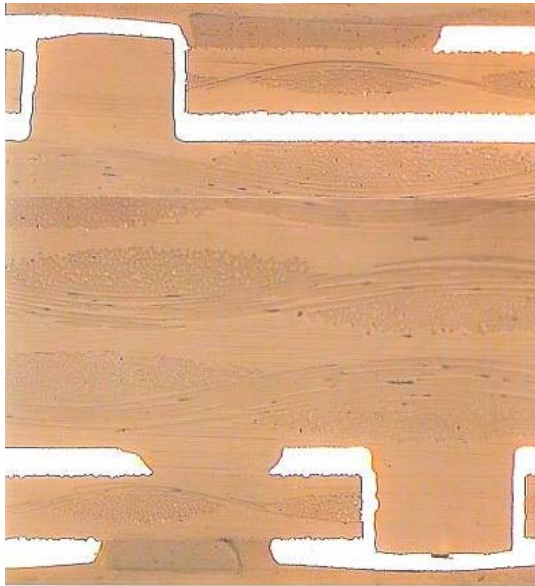
Application : Back Panel

Layer count : 34 layers

Test Results :

- Pass 6 times 288 °C solder float
- No hole wall separation
- No resin recession

Application (V)



Application : Module Card

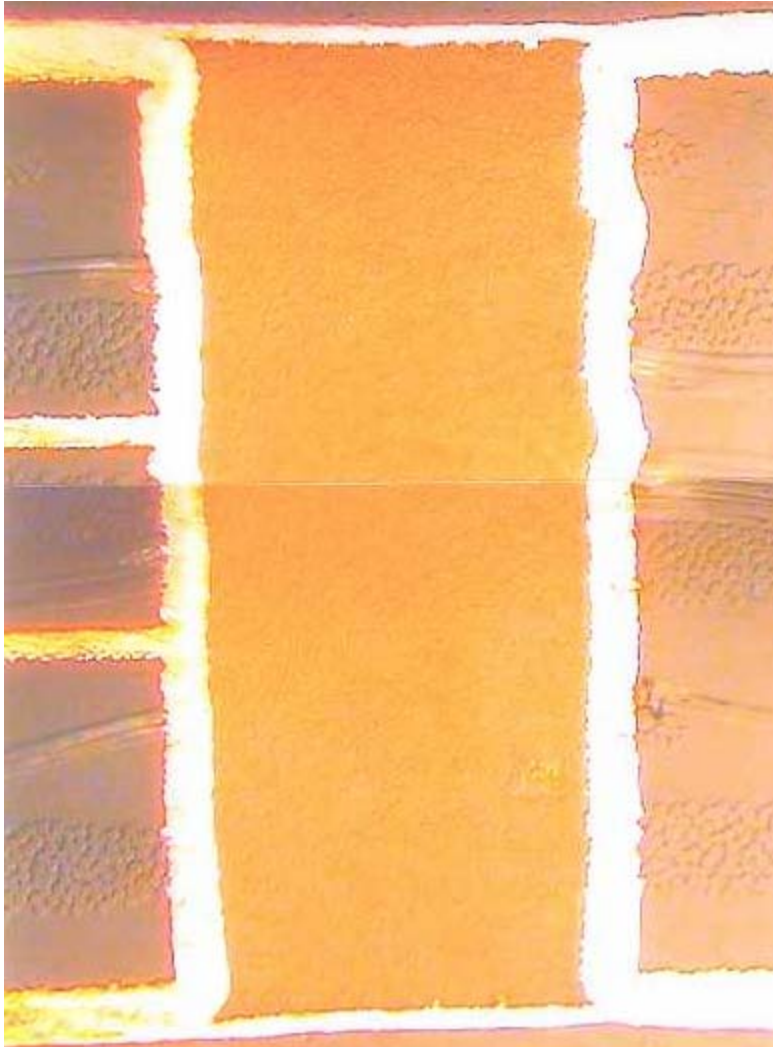
Layer count : 4 layer cap sheet

Blind via

Test Results :

- Pass 5 times 288 °C solder float
- No hole wall separation
- No resin recession

Application (VI)



Application : Chip Packaging

Layer count : 4 layer

Test Results :

- Pass 6 times 288 °C solder float
- No hole wall separation
- No resin recession

Application (VII)

Application : CAF Test

Layer count : 12 layer

Test Condition:

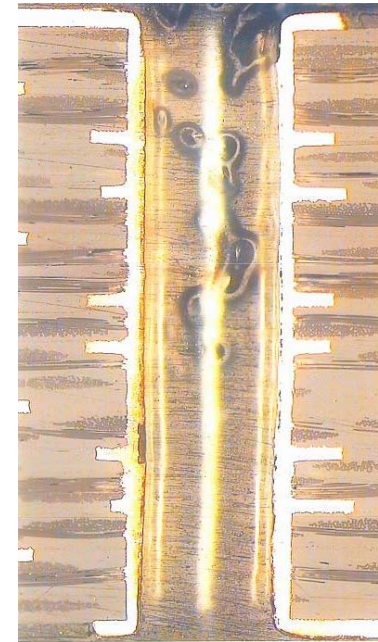
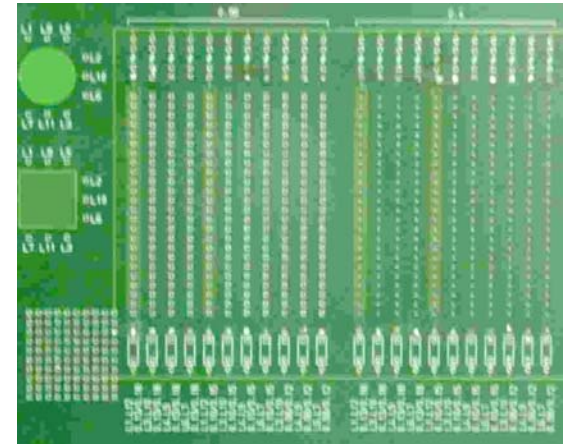
- 85°C/85% Rh 50V bias voltage
100V DC testing
- less than 1 decade resistance drop

Test Results :

- Pass 1000 Hours

*Trace to trace, 0.08mm (3.15 mil)
line width and 0.12mm (4.72mil)
space

*Hole to trace, 0.276mm (10.87 mil)



Thank You

